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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, EBI/EMI, I²C, MMC/SD, QSPI, SCI, SPI, SSI, UART/USART, USB
Peripherals	DMA, LCD, LVD, POR, PWM, WDT
Number of I/O	84
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	96K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 25x14b; D/A 3x8b, 3x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LFQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs3a37a3a01cfp-aa0

Table 1.8 Communication interfaces (2 of 2)

Feature	Functional description
Controller Area Network (CAN) module	The Controller Area Network (CAN) module provides functionality to receive and transmit data using a message-based protocol between multiple slaves and masters in electromagnetically noisy applications. The CAN module complies with the ISO 11898-1 (CAN 2.0A/CAN 2.0B) standard and supports up to 32 mailboxes, which can be configured for transmission or reception in normal mailbox and FIFO modes. Both standard (11-bit) and extended (29-bit) messaging formats are supported. See section 31, Controller Area Network (CAN) Module in User's Manual.
USB 2.0 Full-Speed (USBFS) module	The USB 2.0 Full-Speed (USBFS) module can operate as a host controller or device controller. The module supports full-speed and low-speed (only for the host controller) transfer as defined in the Universal Serial Bus Specification 2.0. The module has an internal USB transceiver and supports all of the transfer types defined in the Universal Serial Bus Specification 2.0. The USB has buffer memory for data transfer, providing a maximum of 10 pipes. Pipes 1 to 9 can be assigned any endpoint number based on the peripheral devices used for communication or based on the user system. The MCU supports revision 1.2 of the Battery Charging Specification. Because the MCU can be powered at 5 V, the USB LDO regulator provides the internal USB transceiver power supply at 3.3 V. See section 28, USB 2.0 Full-Speed Module (USBFS) in User's Manual.
SD/MMC Host Interface (SDHI)	The Secure Digital Host Interface (SDHI) and MultiMediaCard (MMC) interface provide the functionality needed to connect a variety of external memory cards to the MCU. The SDHI supports both 1-bit and 4-bit buses for connecting different memory cards that support SD, SDHC, and SDXC formats. When developing host devices that are compliant with the SD specifications, you must comply with the SD Host/Ancillary Product License Agreement (SD HALA). The MMC interface supports 1-bit, 4-bit, and 8-bit MMC buses that provide eMMC 4.51 (JEDEC Standard JESD 84-B451) device access. This interface also provides backward compatibility and support for high-speed SDR transfer modes. See section 36, SD/MMC Host Interface (SDHI) in User's Manual.

Table 1.9 Analog

Feature	Functional description
14-bit A/D Converter (ADC14)	A 14-bit successive approximation A/D converter is provided. Up to 28 analog input channels are selectable. Temperature sensor output and internal reference voltage are selectable for conversion. The A/D conversion accuracy is selectable from 12-bit and 14-bit conversion making it possible to optimize the tradeoff between speed and resolution in generating a digital value. See section 38, 14-Bit A/D Converter (ADC14) in User's Manual.
12-bit D/A Converter (DAC12)	The 12-bit D/A Converter (DAC12) converts data and includes an output amplifier. See section 39, 12-Bit D/A Converter (DAC12) in User's Manual.
8-bit D/A Converter (DAC8) for ACMPLP	The 8-bit D/A Converter (DAC8) converts data and does not include an output amplifier. The DAC8 is used only as the reference voltage for ACMPLP. See section 43, 8-Bit D/A Converter (DAC8) in User's Manual.
Temperature Sensor (TSN)	The on-chip temperature sensor determines and monitors the die temperature for reliable operation of the device. The sensor outputs a voltage directly proportional to the die temperature, and the relationship between the die temperature and the output voltage is linear. The output voltage is provided to the ADC14 for conversion and can be further used by the end application. See section 40, Temperature Sensor (TSN) in User's Manual.
Low-Power Analog Comparator (ACMPLP)	The Low-Power Analog Comparator (ACMPLP) compares a reference input voltage and analog input voltage. The comparison result can be read by software and also be output externally. The reference voltage can be selected from an input to the CMPREF <i>i</i> (<i>i</i> = 0,1) pin, an internal 8-bit D/A converter output, or the internal reference voltage (<i>Vref</i>) generated internally in the MCU. The ACMPLP response speed can be set before starting an operation. Setting the high-speed mode decreases the response delay time, but increases current consumption. Setting the low-speed mode increases the response delay time, but decreases current consumption. See section 42, Low Power Analog Comparator (ACMPLP) in User's Manual.
Operational Amplifier (OPAMP)	The Operational Amplifier (OPAMP) can be used to amplify small analog input voltages and output the amplified voltages. A total of four differential operational amplifier units with two input pins and one output pin are provided. See section 41, Operational Amplifier (OPAMP) in User's Manual.

1.4 Function Comparison

Table 1.14 Function comparison

Part numbers	R7FS3A37A2A01CLK	R7FS3A37A3A01CFB	R7FS3A37A2A01CBJ	R7FS3A37A3A01CFP	R7FS3A37A2A01CLJ	R7FS3A37A3A01CFM R7FS3A37A3A01CNB
Pin count	145	144	121	100	100	64
Package	LGA	LQFP	BGA	LQFP	LGA	LQFP/QFN
Code flash memory				512 KB		
Data flash memory				8 KB		
SRAM				96 KB		
	Parity			80 KB		
	ECC			16 KB		
System	CPU clock			48 MHz		
	Backup registers			512 bytes		
	ICU			Yes		
	KINT			8		
Event control	ELC			Yes		
DMA	DTC			Yes		
	DMAC			4		
BUS	External bus	16-bit bus		8-bit bus		No
Timers	GPT32			4		
	GPT16			6		
	AGT			2		
	RTC			Yes		
	WDT/IWDT			Yes		
Communication	SCI			6		
	IIC	3			2	
	SPI			2		
	SSIE		1			No
	QSPI		1			No
	SDHI		1			No
	CAN			1		
	USBFS			Yes		
Analog	ADC14	28	26	25		18
	DAC12			1		
	DAC8			2		
	ACMPLP			2		
	OPAMP	4	4	4	4	3
	TSN			Yes		
HMI	SLCDC	4 com x 54 seg or 8 com x 50 seg	4 com x 46 seg or 8 com x 42 seg		4 com x 38 seg or 8 com x 34 seg	4 com x 21 seg or 8 com x 17 seg
	CTSU		27			24
Data processing	CRC			Yes		
	DOC			Yes		
Security				SCE5		

1.7 Pin Lists

Pin number										Timers			Communication interfaces			Analog		HMI							
LGA145	LQFP144	BGA121	LQFP100	LGA100	LQFP64	QFN64	Power, System, Clock, Debug, CAC, VBATT	IRQ0	P400	External bus	AGT	GPT, OPS, POEG	GPT	RTC	USBFS, CAN	SCI	IIC	SPI/QSPI	SSIE	SDHI	ADC14	DAC12, OPAMP	ACMP1LP	SLCDC	CTSU
N13	1	L11	1	J10	1	1	CACR EF	IRQ0	P400		AGTIO 1	GTIOC 6A			SCK1 SCK4	SCL0		AUDIO _CLK					SEG4	TS20	
L11	2	K11	2	J9	2	2		IRQ5	P401		GTET RGA	GTIOC 6B		CTX0	TXD1/ MOSI1 /SDA1 CTS4/ RTS4/ SS4	SDA0							SEG5	TS19	
M13	3	J10	3	F6	3	3	VBAT WIO0	IRQ4	P402		AGTIO 0/ AGTIO 1			RTCIC 0	CRX0	RXD1/ MISO1 /SCL1							SEG6	TS18	
K11	4	J11	4	H10			VBAT WIO1		P403		AGTIO 0/ AGTIO 1	GTIOC 3A	RTCIC 1		CTS1/ RTS1/ SS1			SSIBC K0					TS17		
L12	5	H9	5	G8			VBAT WIO2		P404			GTIOC 3B	RTCIC 2					SSI LR CK0/ SSIFS 0							
L13	6	H10	6	H9					P405			GTIOC 1A						SSITX D0							
J10	7	H11	7	F7					P406			GTIOC 1B						SSLA3 SSIRX D0							
H10	8	G6							P700			GTIOC 5A						MISOA							
K12	9	G7							P701			GTIOC 5B						MOSIA							
K13	10	G8							P702			GTIOC 6A						RSPC KA							
J11	11								P703			GTIOC 6B						SSLA0			VCOUT				
H11	12								P704		AGTO 0							SSLA1							
G11	13								P705		AGTIO 0							SSLA2							
J12	14	G10	8	G9	4	4	VBATT																		
J13	15	G11	9	G10	5	5	VCL																		
H13	16	F11	10	F10	6	6	XCIN		P215																
H12	17	F10	11	F9	7	7	XCOU T		P214																
F12	18	G9	12	D9	8	8	VSS																		
G12	19	E10	13	E9	9	9	XTAL	IRQ2	P213			GTET RGA	GTIOC 0A			TXD1/ MOSI1 /SDA1									
G13	20	E11	14	E10	10	10	EXTAL	IRQ3	P212		AGTE E1	GTET RGB	GTIOC 0B			RXD1/ MISO1 /SCL1									
F13	21	F9	15	D10	11	11	VCC																		
G10	22								P713		AGTO A0	GTIOC 2A													
F11	23								P712		AGTO B0	GTIOC 2B													
E13	24								P711		AGTE E0					CTS1/ RTS1/ SS1									
E12	25	F8							P710	A17						SCK1									
F10	26	F7							IRQ10	P709						TXD1/ MOSI1 /SDA1									
D13	27	E9	16	F8					IRQ11	P708						RXD1/ MISO1 /SCL1		SSLA3							
E11	28	D10	17	E8					IRQ8	P415						GTIOC 0A			SSLA2		SD0C D				
D12	29	D11	18	E7					IRQ9	P414						GTIOC 0B			SSLA1		SD0W P				
E10	30	E8	19	C9					P413			GTOU UP				CTS0/ RTS0/ SS0		SSLA0		SD0CL K					
C13	31	D9	20	C10					P412			GTOU LO				SCK0		RSPC KA		SD0C MD					

2.2.7 P408, P409 I/O Pin Output Characteristics of Middle Drive Capacity

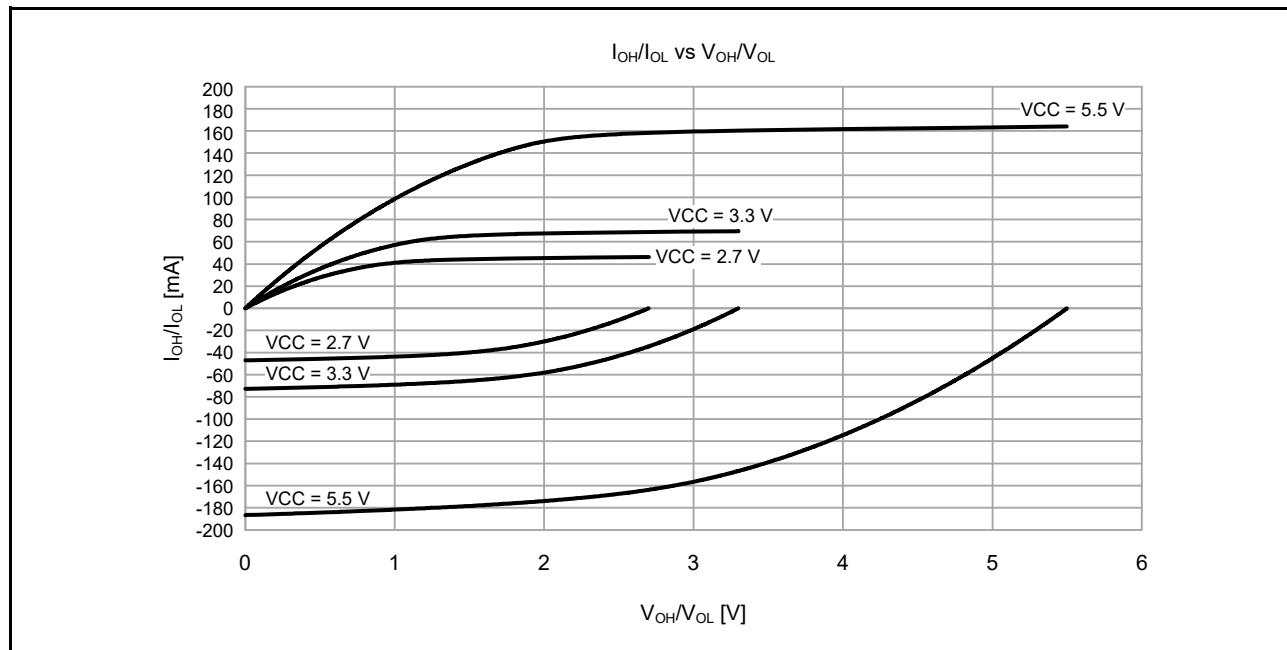


Figure 2.12 V_{OH}/V_{OL} and I_{OH}/I_{OL} voltage characteristics at $T_a = 25^\circ\text{C}$ when middle drive output is selected (reference data)

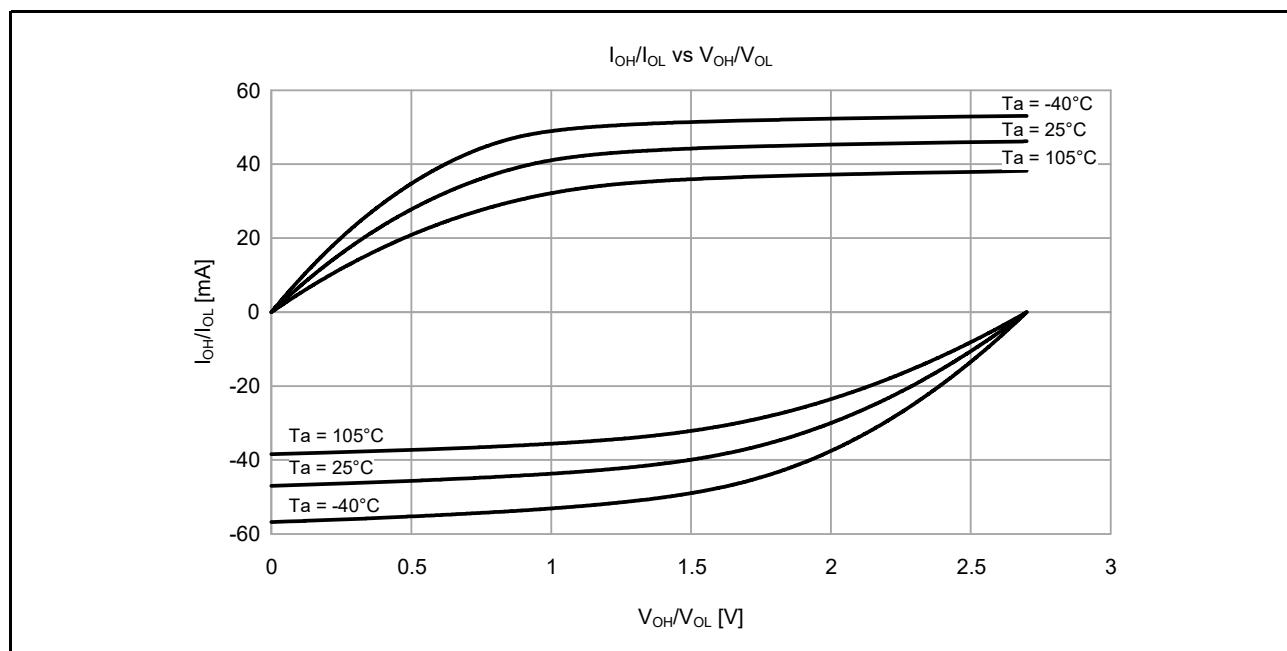


Figure 2.13 V_{OH}/V_{OL} and I_{OH}/I_{OL} temperature characteristics at $V_{CC} = 2.7\text{ V}$ when middle drive output is selected (reference data)

2.2.8 IIC I/O Pin Output Characteristics

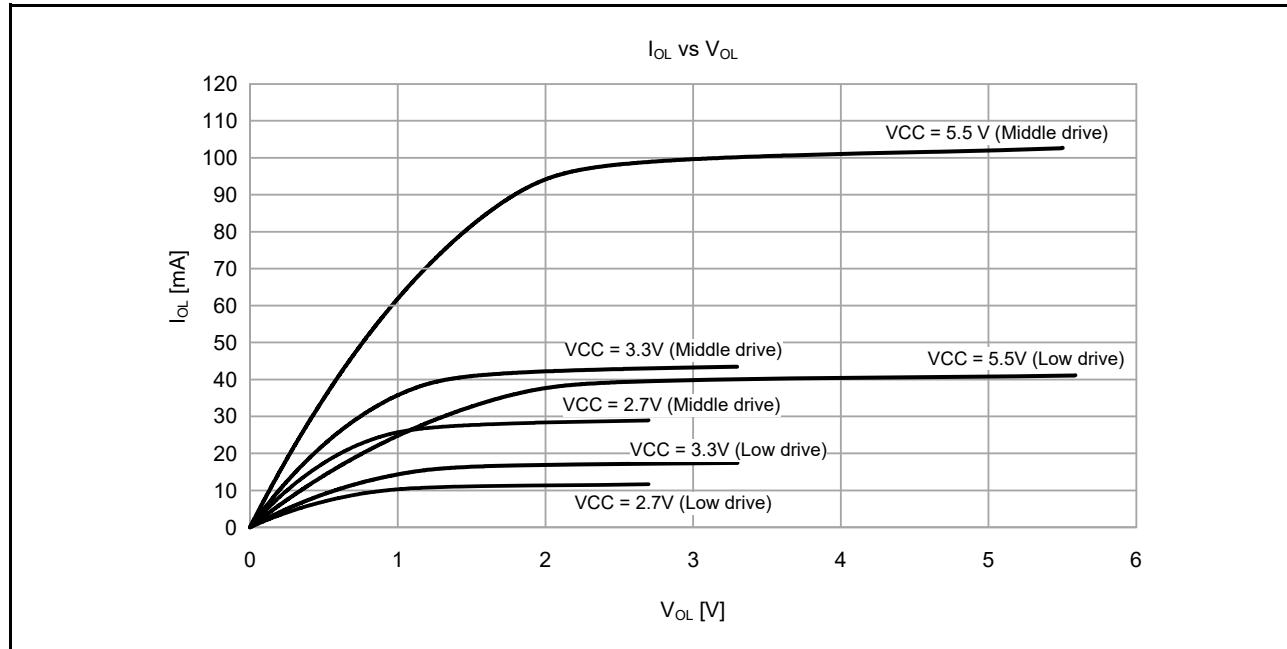


Figure 2.16 V_{OH}/V_{OL} and I_{OH}/I_{OL} voltage characteristics at $T_a = 25^\circ\text{C}$

2.3 AC Characteristics

2.3.1 Frequency

Table 2.17 Operation frequency value in high-speed operating mode

Conditions: VCC = AVCC0 = 2.4 to 5.5 V

Parameter		Symbol	Min	Typ	Max ^{*5}	Unit	
Operation frequency	System clock (ICLK) ^{*4}	f	2.7 to 5.5 V	0.032768	-	48	
			2.4 to 2.7 V	0.032768	-	16	
	FlashIF clock (FCLK) ^{*1, *2, *4}		2.7 to 5.5 V	0.032768	-	32	
			2.4 to 2.7 V	0.032768	-	16	
	Peripheral module clock (PCLKA) ^{*4}		2.7 to 5.5 V	-	-	48	
			2.4 to 2.7 V	-	-	16	
	Peripheral module clock (PCLKB) ^{*4}		2.7 to 5.5 V	-	-	32	
			2.4 to 2.7 V	-	-	16	
	Peripheral module clock (PCLKC) ^{*3, *4}		2.7 to 5.5 V	-	-	64	
			2.4 to 2.7 V	-	-	16	
	Peripheral module clock (PCLKD) ^{*4}		2.7 to 5.5 V	-	-	64	
			2.4 to 2.7 V	-	-	16	
	External bus clock (BCLK) ^{*4}		2.7 to 5.5 V	-	-	24	
			2.4 to 2.7 V	-	-	16	
	EBCLK pin output		2.7 to 5.5 V	-	-	12	
			2.4 to 2.7 V	-	-	8	

- Note 1. The lower-limit frequency of FCLK is 1 MHz while programming or erasing the flash memory. When using FCLK for programming or erasing the flash memory at below 4 MHz, the frequency can be set to 1 MHz, 2 MHz, or 3 MHz. A non-integer frequency such as 1.5 MHz cannot be set.
- Note 2. The frequency accuracy of FCLK must be $\pm 3.5\%$ while programming or erasing the flash memory. Confirm the frequency accuracy of the clock source.
- Note 3. The lower-limit frequency of PCLKC is 4 MHz at 2.4 V or above and 1 MHz at below 2.4 V when the 14-bit A/D converter is in use.
- Note 4. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.
- Note 5. The maximum value of operation frequency does not include the internal oscillator errors. The operation can be guaranteed with the errors of the internal oscillator. For details on the range for guaranteed operation, see [Table 2.22, Clock timing](#).

Note 3. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.

Note 4. The maximum value of operation frequency does not include the internal oscillator errors. The operation can be guaranteed with the errors of the internal oscillator. For details on the range for guaranteed operation, see [Table 2.22, Clock timing](#).

Table 2.20 Operation frequency value in low-voltage mode

Conditions: VCC = AVCC0 = 1.6 to 5.5 V

Parameter			Symbol	Min	Typ	Max ^{*5}	Unit
Operation frequency	System clock (ICLK) ^{*4}	1.6 to 5.5 V	f	0.032768	-	4	MHz
	FlashIF clock (FCLK) ^{*1, *2, *4}	1.6 to 5.5 V		0.032768	-	4	
	Peripheral module clock (PCLKA) ^{*4}	1.6 to 5.5 V		-	-	4	
	Peripheral module clock (PCLKB) ^{*4}	1.6 to 5.5 V		-	-	4	
	Peripheral module clock (PCLKC) ^{*3, *4}	1.6 to 5.5 V		-	-	4	
	Peripheral module clock (PCLKD) ^{*4}	1.6 to 5.5 V		-	-	4	
	External bus clock (BCLK) ^{*4}	1.6 to 5.5 V		-	-	4	
	EBCLK pin output	1.8 to 5.5 V		-	-	4	
		1.6 to 1.8 V		-	-	2	

Note 1. The lower-limit frequency of FCLK is 1 MHz while programming or erasing the flash memory. When using FCLK for programming or erasing the flash memory at below 4 MHz, the frequency can be set to 1 MHz, 2 MHz, or 3 MHz. A non-integer frequency such as 1.5 MHz cannot be set.

Note 2. The frequency accuracy of FCLK must be $\pm 3.5\%$ while programming or erasing the flash memory. Confirm the frequency accuracy of the clock source.

Note 3. The lower-limit frequency of PCLKC is 4 MHz at 2.4 V or above and 1 MHz at below 2.4 V when the 14-bit A/D converter is in use.

Note 4. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.

Note 5. The maximum value of operation frequency does not include errors of the internal oscillator. The operation can be guaranteed with the errors of the internal oscillator. For details on the range for guaranteed operation, see [Table 2.22, Clock timing](#).

Table 2.21 Operation frequency value in Subosc-speed mode

Conditions: VCC = AVCC0 = 1.8 to 5.5 V

Parameter			Symbol	Min	Typ	Max	Unit
Operation frequency	System clock (ICLK) ^{*3}	1.8 to 5.5 V	f	27.8528	32.768	37.6832	kHz
	FlashIF clock (FCLK) ^{*1, *3}	1.8 to 5.5 V		27.8528	32.768	37.6832	
	Peripheral module clock (PCLKA) ^{*3}	1.8 to 5.5 V		-	-	37.6832	
	Peripheral module clock (PCLKB) ^{*3}	1.8 to 5.5 V		-	-	37.6832	
	Peripheral module clock (PCLKC) ^{*2, *3}	1.8 to 5.5 V		-	-	37.6832	
	Peripheral module clock (PCLKD) ^{*3}	1.8 to 5.5 V		-	-	37.6832	
	External bus clock (BCLK) ^{*3}	1.8 to 5.5 V		-	-	37.6832	
	EBCLK pin output	1.8 to 5.5 V		-	-	37.6832	

Note 1. Programming and erasing the flash memory is not possible.

Note 2. The 14-bit A/D converter cannot be used.

Note 3. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.

2.3.2 Clock Timing

Table 2.22 Clock timing (1 of 2)

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions
EBCLK pin output cycle time	t_{Bcyc}	83.3	-	-	ns	Figure 2.26
		125	-	-		
		500	-	-		
EBCLK pin output high pulse width	t_{CH}	20	-	-	ns	
		30	-	-		
		150	-	-		
EBCLK pin output low pulse width	t_{CL}	20	-	-	ns	
		30	-	-		
		150	-	-		
EBCLK pin output rise time	t_{Cr}	-	-	15	ns	
		-	-	25		
		-	-	30		
		-	-	50		
EBCLK pin output fall time	t_{Cf}	-	-	15	ns	
		-	-	25		
		-	-	30		
		-	-	50		
EXTAL external clock input cycle time	t_{Xcyc}	50	-	-	ns	Figure 2.27
EXTAL external clock input high pulse width	t_{XH}	20	-	-	ns	
EXTAL external clock input low pulse width	t_{XL}	20	-	-	ns	
EXTAL external clock rising time	t_{Xr}	-	-	5	ns	
EXTAL external clock falling time	t_{Xf}	-	-	5	ns	
EXTAL external clock input wait time*1	t_{EXWT}	0.3	-	-	μs	
EXTAL external clock input frequency	f_{EXTAL}	-	-	20	MHz	2.4 ≤ VCC ≤ 5.5
		-	-	8		1.8 ≤ VCC < 2.4
		-	-	1		1.6 ≤ VCC < 1.8
Main clock oscillator oscillation frequency	f_{MAIN}	1	-	20	MHz	2.4 ≤ VCC ≤ 5.5
		1	-	8		1.8 ≤ VCC < 2.4
		1	-	4		1.6 ≤ VCC < 1.8
Main clock oscillation stabilization wait time (crystal)*9	$t_{MAINOSCWT}$	-	-	-*9	ms	
LOCO clock oscillation frequency	f_{LOCO}	27.8528	32.768	37.6832	kHz	-
LOCO clock oscillation stabilization time	t_{LOCO}	-	-	100	μs	Figure 2.28
IWDT-dedicated clock oscillation frequency	f_{ILOCO}	12.75	15	17.25	kHz	-
MOCO clock oscillation frequency	f_{MOCO}	6.8	8	9.2	MHz	-
MOCO clock oscillation stabilization time	t_{MOCO}	-	-	1	μs	-

2.3.3 Reset Timing

Table 2.23 Reset timing

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions
RES pulse width	At power-on	t_{RESWP}	3	-	-	ms
	Other than above	t_{RESW}	30	-	-	μs
Wait time after RES cancellation (at power-on)	LVD0: enable*1	t_{RESWT}	-	0.7	-	ms
	LVD0: disable*2		-	0.3	-	
Wait time after RES cancellation (during powered-on state)	LVD0: enable*1	t_{RESWT2}	-	0.5	-	ms
	LVD0: disable*2		-	0.05	-	
Internal reset cancellation time (Watchdog timer reset, SRAM parity error reset, SRAM ECC error reset, Bus master MPU error reset, Bus slave MPU error reset, Stack pointer error reset, Software reset)	LVD0: enable*1	t_{RESWT3}	-	0.6	-	ms
	LVD0: disable*2		-	0.15	-	

Note 1. When OFS1.LVDAS = 0.

Note 2. When OFS1.LVDAS = 1.

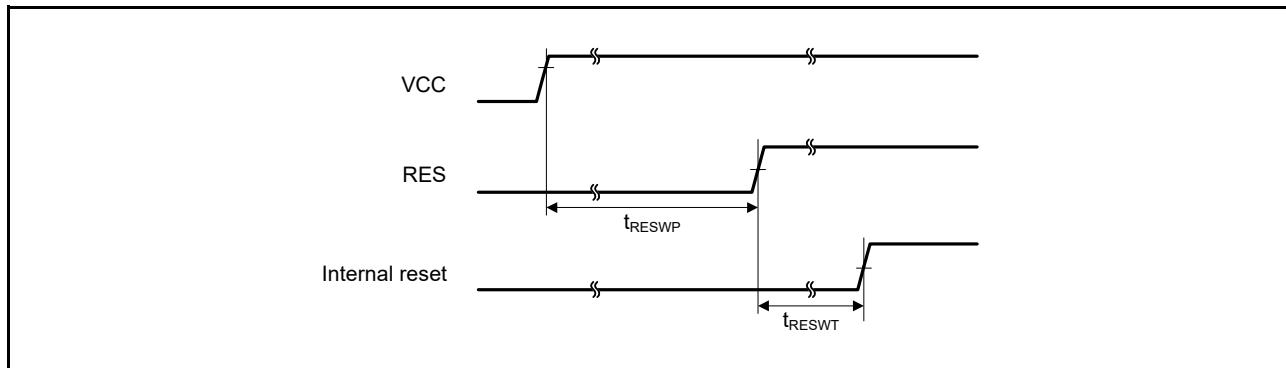


Figure 2.34 Reset input timing at power-on

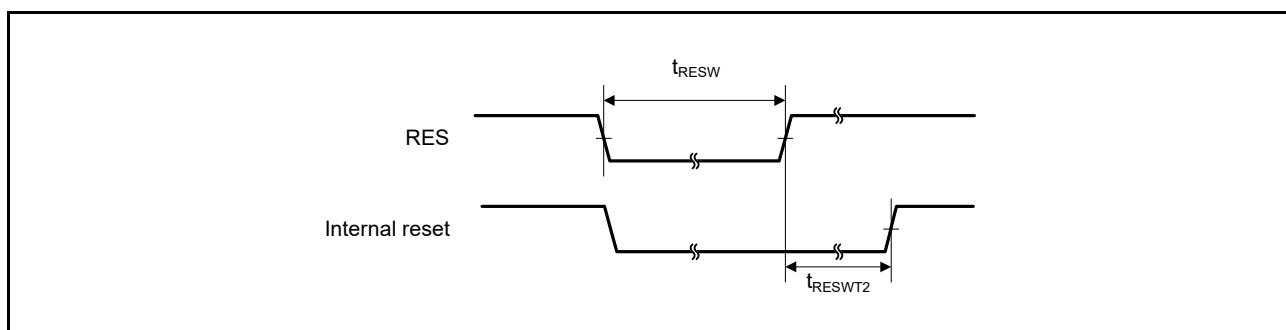


Figure 2.35 Reset input timing (1)

2.3.5 NMI and IRQ Noise Filter

Table 2.30 NMI and IRQ noise filter

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions	
NMI pulse width	t_{NMIW}	200	-	-	ns	NMI digital filter disabled	$t_{Pcyc} \times 2 \leq 200 \text{ ns}$
		$t_{Pcyc} \times 2^{*1}$	-	-			$t_{Pcyc} \times 2 > 200 \text{ ns}$
		200	-	-	ns	NMI digital filter enabled	$t_{NMICK} \times 3 \leq 200 \text{ ns}$
		$t_{NMICK} \times 3.5^{*2}$	-	-			$t_{NMICK} \times 3 > 200 \text{ ns}$
IRQ pulse width	t_{IRQW}	200	-	-	ns	IRQ digital filter disabled	$t_{Pcyc} \times 2 \leq 200 \text{ ns}$
		$t_{Pcyc} \times 2^{*1}$	-	-			$t_{Pcyc} \times 2 > 200 \text{ ns}$
		200	-	-	ns	IRQ digital filter enabled	$t_{IRQCK} \times 3 \leq 200 \text{ ns}$
		$t_{IRQCK} \times 3.5^{*3}$	-	-			$t_{IRQCK} \times 3 > 200 \text{ ns}$

Note: 200 ns minimum in Software Standby mode.

Note 1. t_{Pcyc} indicates the cycle of PCLKB.

Note 2. t_{NMICK} indicates the cycle of the NMI digital filter sampling clock.

Note 3. t_{IRQCK} indicates the cycle of the IRQ*i* digital filter sampling clock (*i* = 0 to 15).

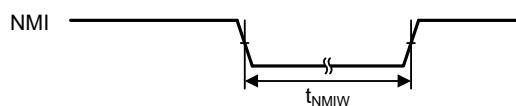


Figure 2.38 NMI interrupt input timing

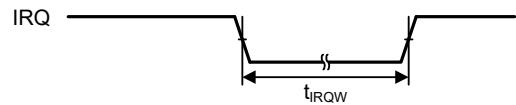


Figure 2.39 IRQ interrupt input timing

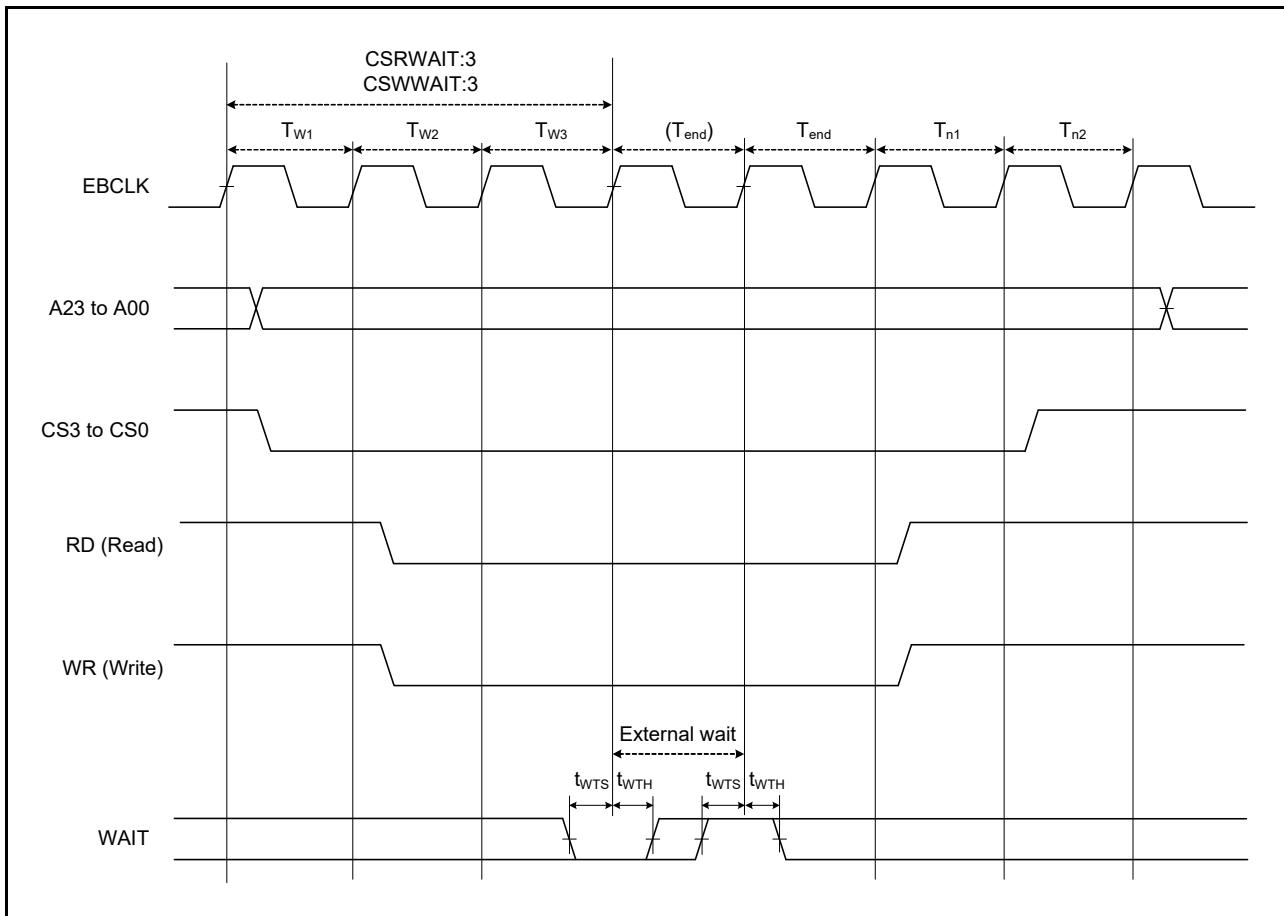


Figure 2.46 External bus timing/external wait control

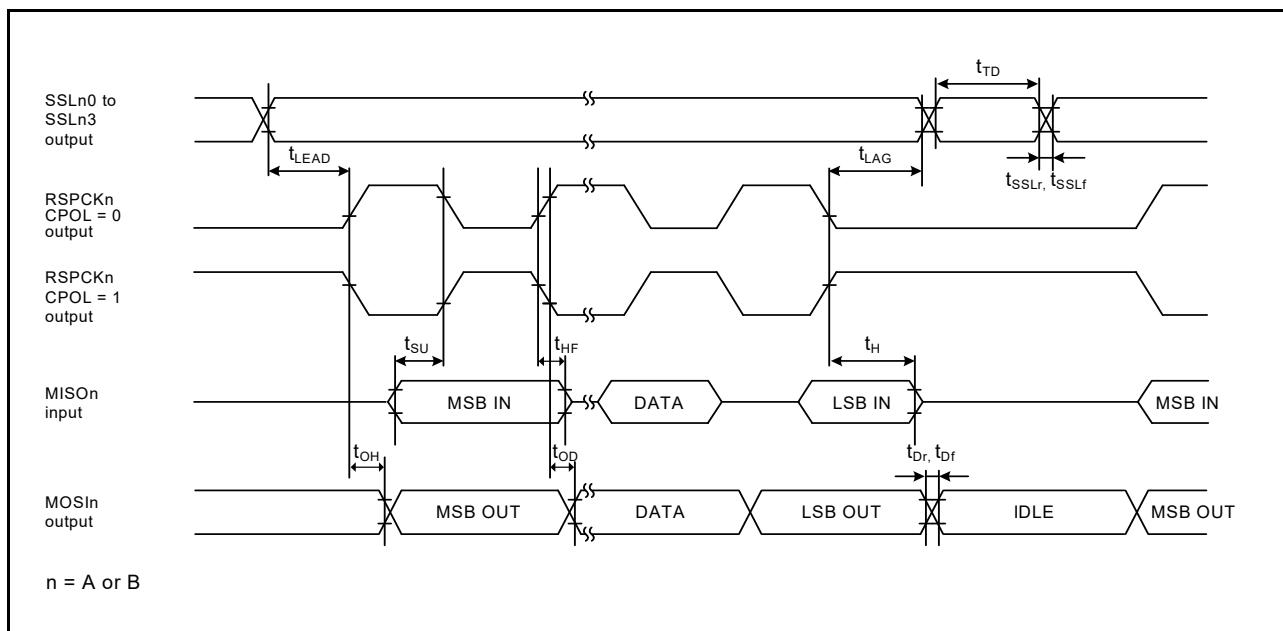


Figure 2.65 SPI timing (master, CPHA = 1) (bit rate: PCLKA division ratio is set to 1/2)

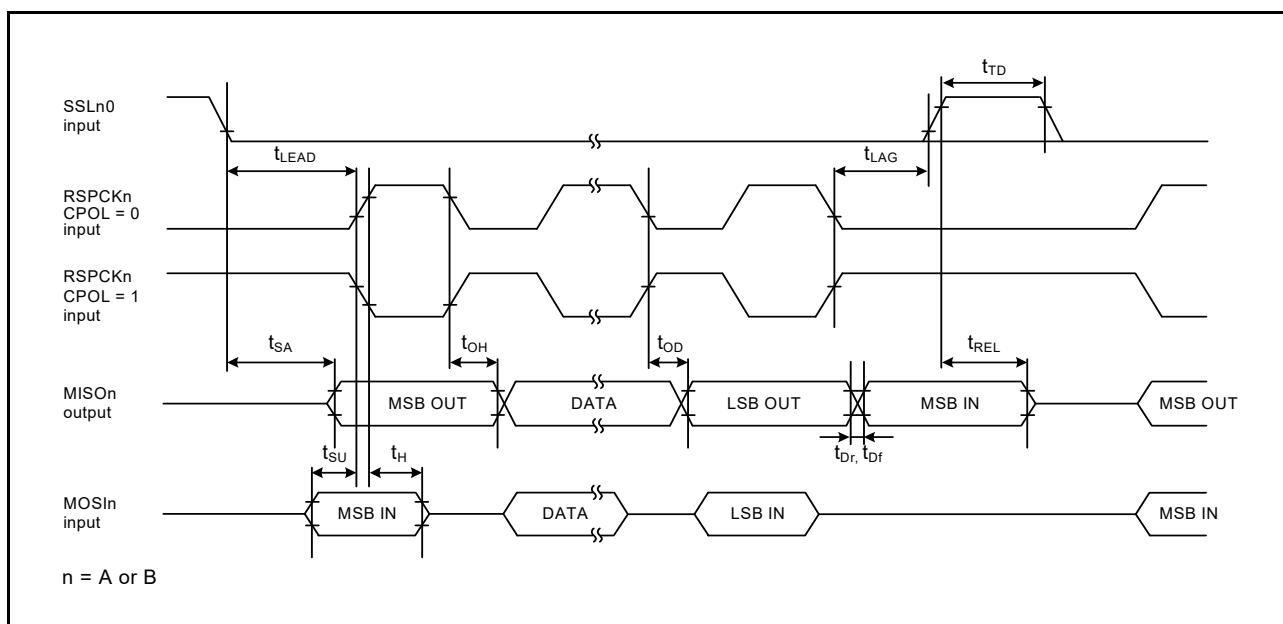


Figure 2.66 SPI timing (slave, CPHA = 0)

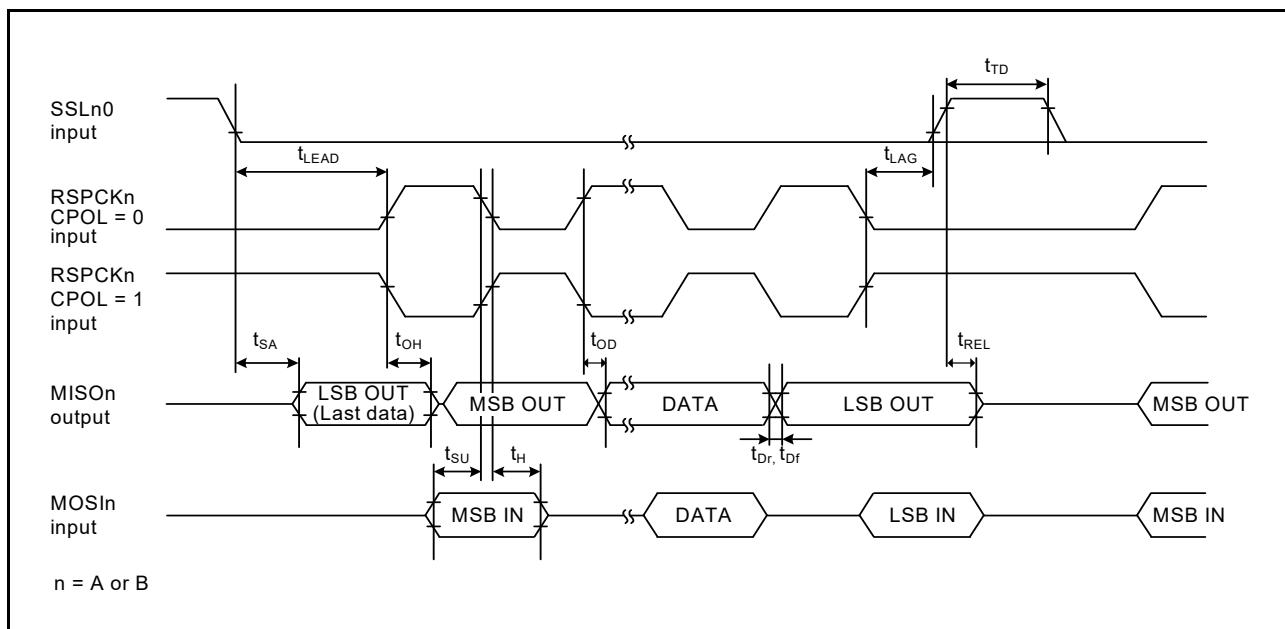


Figure 2.67 SPI timing (slave, CPHA = 1)

2.3.11 QSPI Timing

Table 2.41 QSPI timing

Conditions: VCC = 1.8 to 5.5 V

Conditions: Middle drive output is selected in the Port Drive Capability bit in PmnPFS register

Parameter		Symbol	Min	Max	Unit ^{*1}	Test conditions
QSPI	QSPCLK clock cycle	t _{QScyc}	2 ^{*4}	48	t _{Pcyc}	Figure 2.68
	QSPCLK clock high-level pulse width	t _{QSWH}	t _{QScyc} × 0.4	-	ns	
	QSPCLK clock low-level pulse width	t _{QSWL}	t _{QScyc} × 0.4	-	ns	
	Data input setup time	t _{SI}	25	-	ns	
	Data input hold time	t _{IH}	2	-	ns	
	SSL setup time	t _{LEAD}	(N + 0.5) × t _{QScyc} - 15 ^{*2}	(N + 0.5) × t _{QScyc} + 100 ^{*2}	ns	
	SSL hold time	t _{LAG}	(N + 0.5) × t _{QScyc} - 15 ^{*3}	(N + 0.5) × t _{QScyc} + 100 ^{*3}	ns	
	Data output delay	t _{OD}	-	14	ns	Figure 2.69
	2.7 V or above		-	20		
	1.8 V or above		-	30		
Data output hold time	2.7 V or above	t _{OH}	-3.3	-	ns	
	1.8 V or above		-10	-		
Successive transmission delay		t _{TD}	1	16	t _{QScyc}	

Note 1. t_{Pcyc}: PCLKA cycle.

Note 2. N is set to 0 or 1 in SFMSLD.

Note 3. N is set to 0 or 1 in SFMSHD.

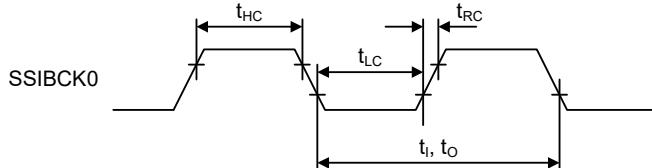
Note 4. The upper limit of QSPCLK is 16MHz.

2.3.13 SSIE Timing

Table 2.43 SSIE timing

Conditions: VCC = 1.6 to 5.5 V

Parameter			Symbol	Min	Max	Unit	Test conditions	
SSIE	AUDIO_CLK input frequency	2.7 V or above	t _{AUDIO}	-	25	MHz	-	
		1.6 V or above		-	4			
	Output clock period		t _O	250	-	ns	Figure 2.71 Figure 2.72, Figure 2.73	
	Input clock period		t _I	250	-	ns		
	Clock high pulse width	1.8 V or above	t _{HC}	100	-	ns		
		1.6 V or above		200	-			
	Clock low pulse width	1.8 V or above	t _{LC}	100	-	ns		
		1.6 V or above		200	-			
	Clock rise time		t _{RC}	-	25	ns		
	Data delay	2.7 V or above	t _{DTR}	-	65	ns		
		1.8 V or above		-	105			
		1.6 V or above		-	140			
	Set-up time	2.7 V or above	t _{SR}	65	-	ns		
		1.8 V or above		90	-			
		1.6 V or above		140	-			
	Hold time		t _{HTR}	40	-	ns		
	SSITXDO output delay from SSILRCK/SSIFS change time	1.8 V or above	T _{DTRW}	-	105	ns	Figure 2.74	
		1.6 V or above		-	140			

**Figure 2.71 SSIE clock input/output timing**

2.5 ADC14 Characteristics

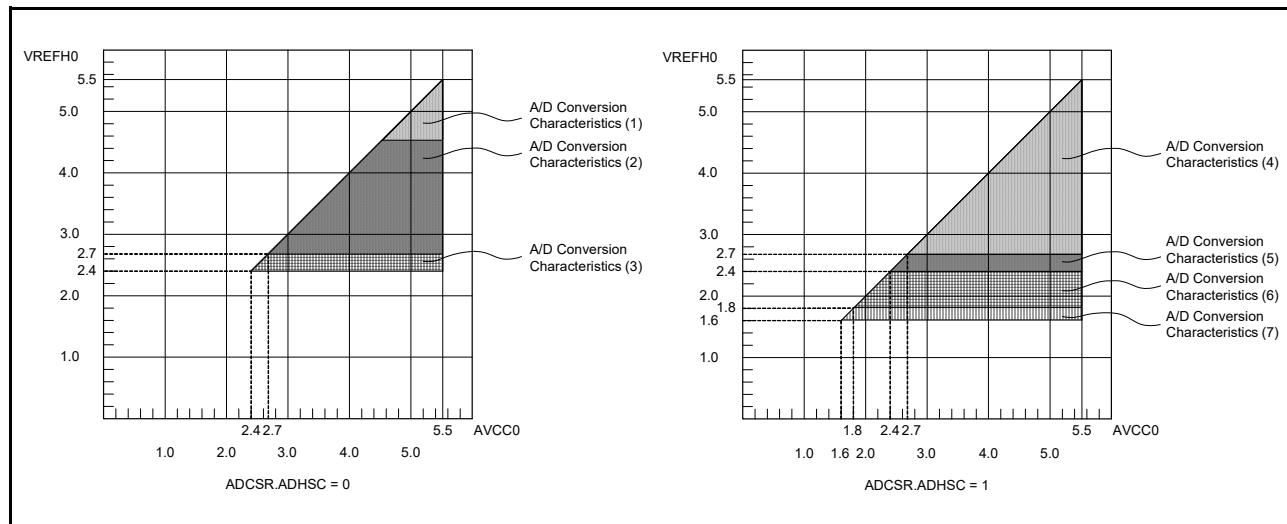


Figure 2.80 AVCC0 to VREFH0 voltage range

Table 2.48 A/D conversion characteristics (1) in high-speed A/D conversion mode (1 of 2)

Conditions: VCC = AVCC0 = 4.5 to 5.5 V, VREFH0 = 4.5 to 5.5 V

Reference voltage range applied to the VREFH0 and VREFL0.

Parameter	Min	Typ	Max	Unit	Test conditions	
Frequency	1	-	64	MHz	-	
Analog input capacitance ^{*2}	Cs	-	8 (reference data)	pF	High-precision channel	
		-	9 (reference data)	pF	Normal-precision channel	
Analog input resistance	Rs	-	2.5 (reference data)	kΩ	High-precision channel	
		-	6.7 (reference data)	kΩ	Normal-precision channel	
Analog input voltage range	Ain	0	-	VREFH0	V	
12-bit mode						
Resolution	-	-	12	Bit	-	
Conversion time ^{*1} (Operation at PCLKC = 64 MHz)	Permissible signal source impedance Max. = 0.3 kΩ	0.70	-	-	µs High-precision channel ADCSR.ADHSC = 0 ADSSTRn.SST[7:0] = 0Dh	
		1.13	-	-	µs Normal-precision channel ADCSR.ADHSC = 0 ADSSTRn.SST[7:0] = 28h	
Offset error		-	±0.5	±4.5 ±6.0	LSB High-precision channel Other than above	
Full-scale error		-	±0.75	±4.5 ±6.0	LSB High-precision channel Other than above	
Quantization error		-	±0.5	-	LSB -	
Absolute accuracy		-	±1.25	±5.0 ±8.0	LSB High-precision channel Other than above	
DNL differential nonlinearity error		-	±1.0	-	LSB -	
INL integral nonlinearity error		-	±1.0	±3.0	LSB -	
14-bit mode						
Resolution	-	-	14	Bit	-	

2.9 POR and LVD Characteristics

Table 2.62 Power-on reset circuit and voltage detection circuit characteristics (1)

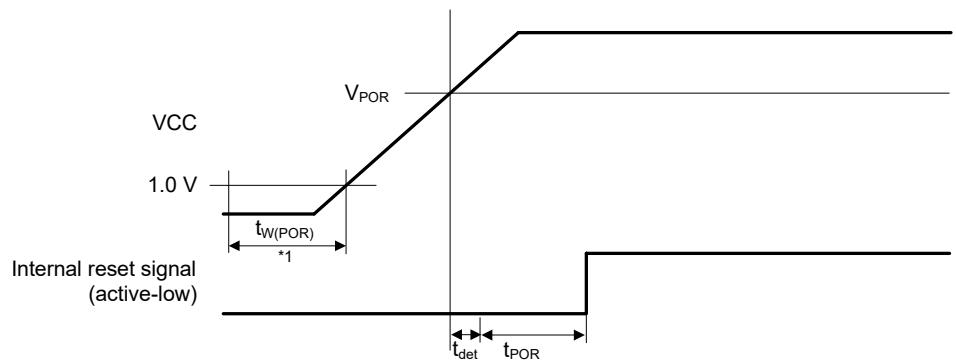
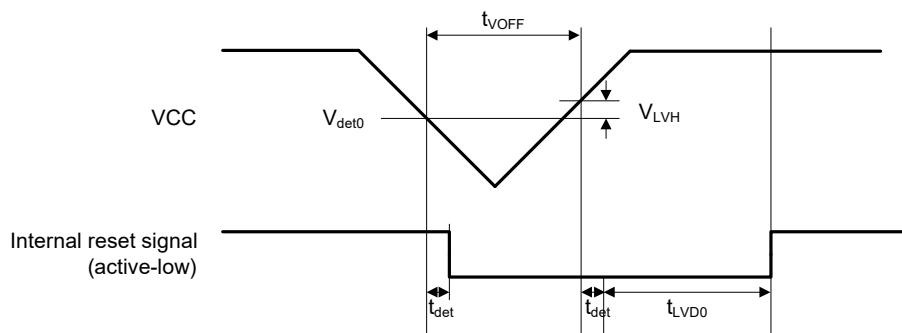
Parameter	Symbol	Min	Typ	Max	Unit	Test conditions
Voltage detection level* ¹	V_{POR}	1.27	1.42	1.57	V	Figure 2.85 , Figure 2.86
Voltage detection circuit (LVD0)* ²	V_{det0_0}	3.68	3.85	4.00	V	Figure 2.87 At falling edge VCC
	V_{det0_1}	2.68	2.85	2.96		
	V_{det0_2}	2.38	2.53	2.64		
	V_{det0_3}	1.78	1.90	2.02		
	V_{det0_4}	1.60	1.69	1.82		
Voltage detection circuit (LVD1)* ³	V_{det1_0}	4.13	4.29	4.45	V	Figure 2.88 At falling edge VCC
	V_{det1_1}	3.98	4.16	4.30		
	V_{det1_2}	3.86	4.03	4.18		
	V_{det1_3}	3.68	3.86	4.00		
	V_{det1_4}	2.98	3.10	3.22		
	V_{det1_5}	2.89	3.00	3.11		
	V_{det1_6}	2.79	2.90	3.01		
	V_{det1_7}	2.68	2.79	2.90		
	V_{det1_8}	2.58	2.68	2.78		
	V_{det1_9}	2.48	2.58	2.68		
	V_{det1_A}	2.38	2.48	2.58		
	V_{det1_B}	2.10	2.20	2.30		
	V_{det1_C}	1.84	1.96	2.05		
	V_{det1_D}	1.74	1.86	1.95		
	V_{det1_E}	1.63	1.75	1.84		
	V_{det1_F}	1.60	1.65	1.73		
Voltage detection circuit (LVD2)* ⁴	V_{det2_0}	4.11	4.31	4.48	V	Figure 2.89 At falling edge VCC
	V_{det2_1}	3.97	4.17	4.34		
	V_{det2_2}	3.83	4.03	4.20		
	V_{det2_3}	3.64	3.84	4.01		

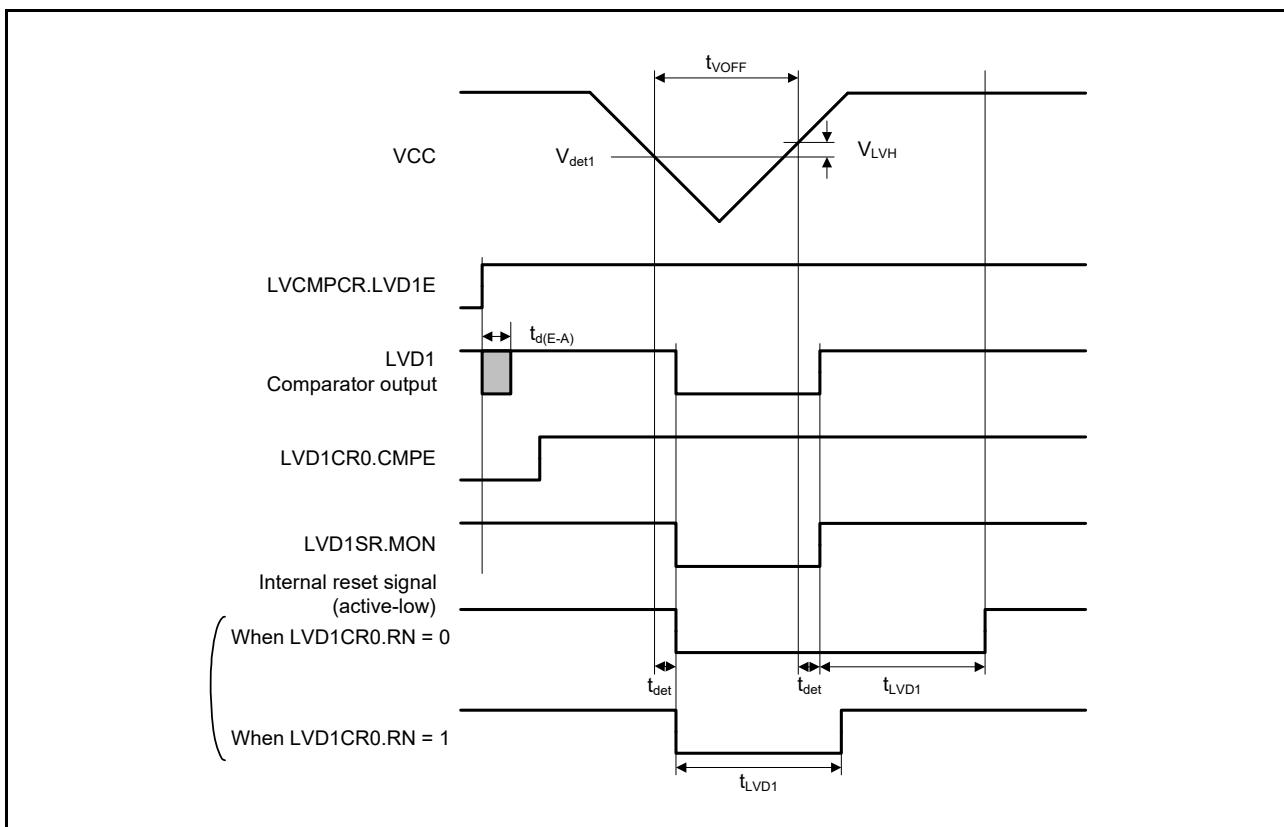
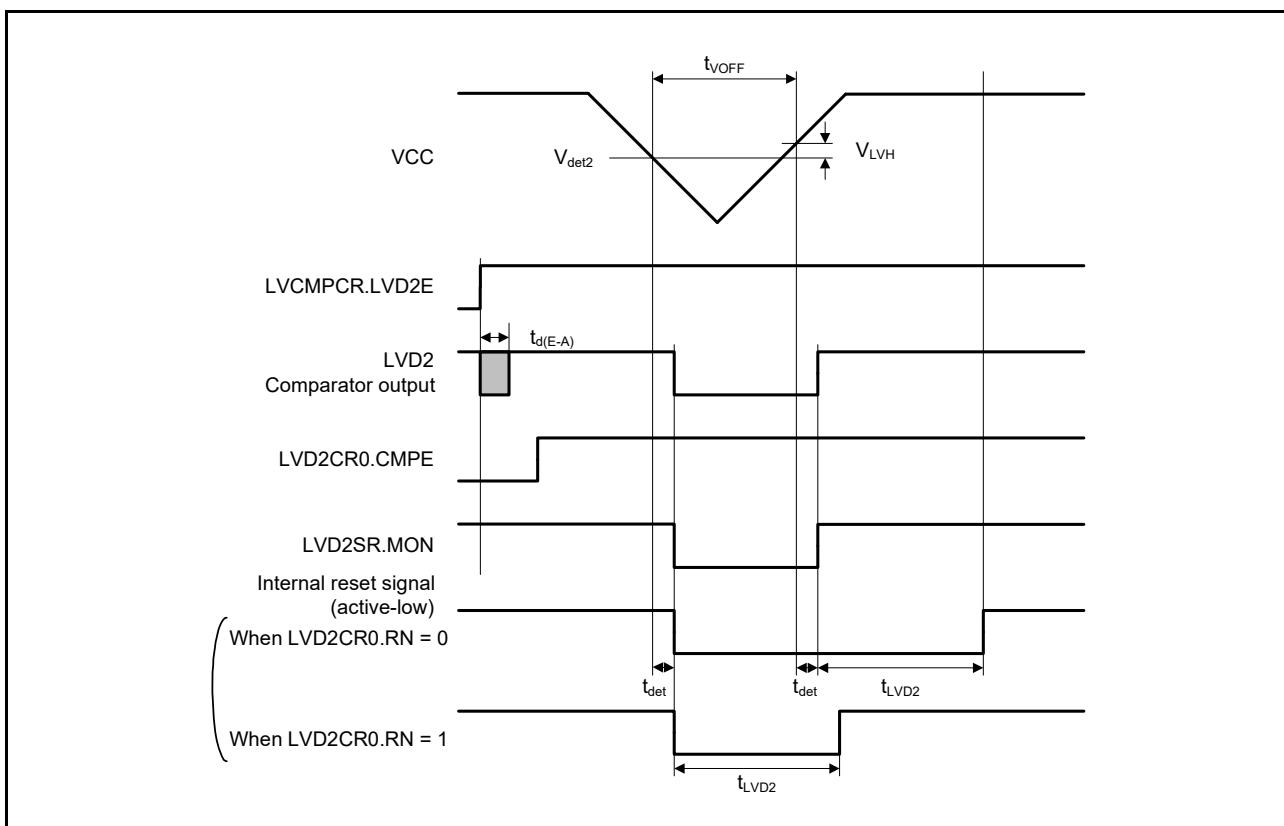
Note 1. These characteristics apply when noise is not superimposed on the power supply. When a setting causes this voltage detection level to overlap with that of the voltage detection circuit, it cannot be specified whether LVD1 or LVD2 is used for voltage detection.

Note 2. # in the symbol $V_{det0_#}$ denotes the value of the OFS1.VDSEL1[2:0] bits.

Note 3. # in the symbol $V_{det1_#}$ denotes the value of the LVDLVLR.LVD1LVL[4:0] bits.

Note 4. # in the symbol $V_{det2_#}$ denotes the value of the LVDLVLR.LVD2LVL[2:0] bits.

**Figure 2.86** Power-on reset timing**Figure 2.87** Voltage detection circuit timing (V_{det0})

Figure 2.88 Voltage detection circuit timing (V_{det1})Figure 2.89 Voltage detection circuit timing (V_{det2})

2.12.3 Capacitor Split Method

[1/3 Bias Method]

Table 2.72 Internal voltage boosting method LCD characteristics

Conditions: VCC = 2.2 V to 5.5 V

Parameter	Symbol	Conditions	Min	Typ	Max	Unit	Test conditions
VL4 voltage*1	V _{L4}	C1 to C4 = 0.47 μ F*2	-	VCC	-	V	-
VL2 voltage*1	V _{L2}	C1 to C4 = 0.47 μ F*2	2/3 \times V _{L4} - 0.07	2/3 \times V _{L4}	2/3 \times V _{L4} + 0.07	V	-
VL1 voltage*1	V _{L1}	C1 to C4 = 0.47 μ F*2	1/3 \times V _{L4} - 0.08	1/3 \times V _{L4}	1/3 \times V _{L4} + 0.08	V	-
Capacitor split wait time*1	t _{WAIT}		100	-	-	ms	Figure 2.93

Note 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).

Note 2. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between VL1 and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL4 and GND
- C1 = C2 = C3 = C4 = 0.47 μ F \pm 30%.

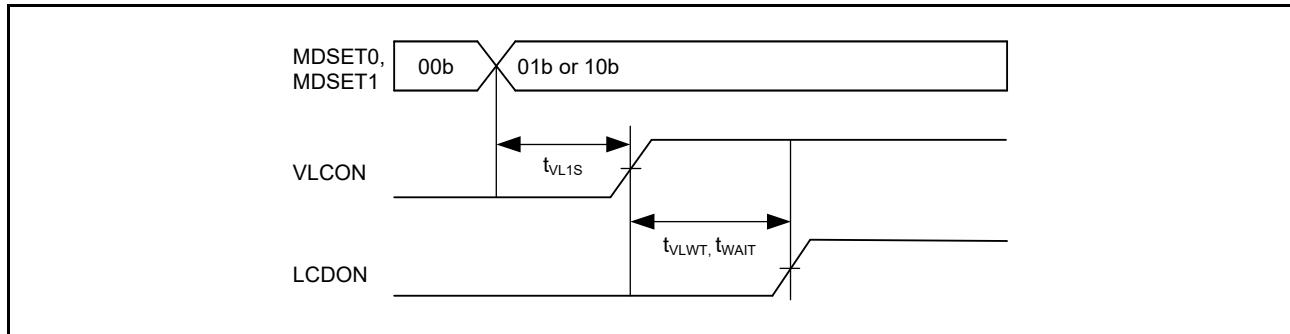


Figure 2.93 LCD reference voltage setup time, voltage boosting wait time, and capacitor split wait time

2.13 Comparator Characteristics

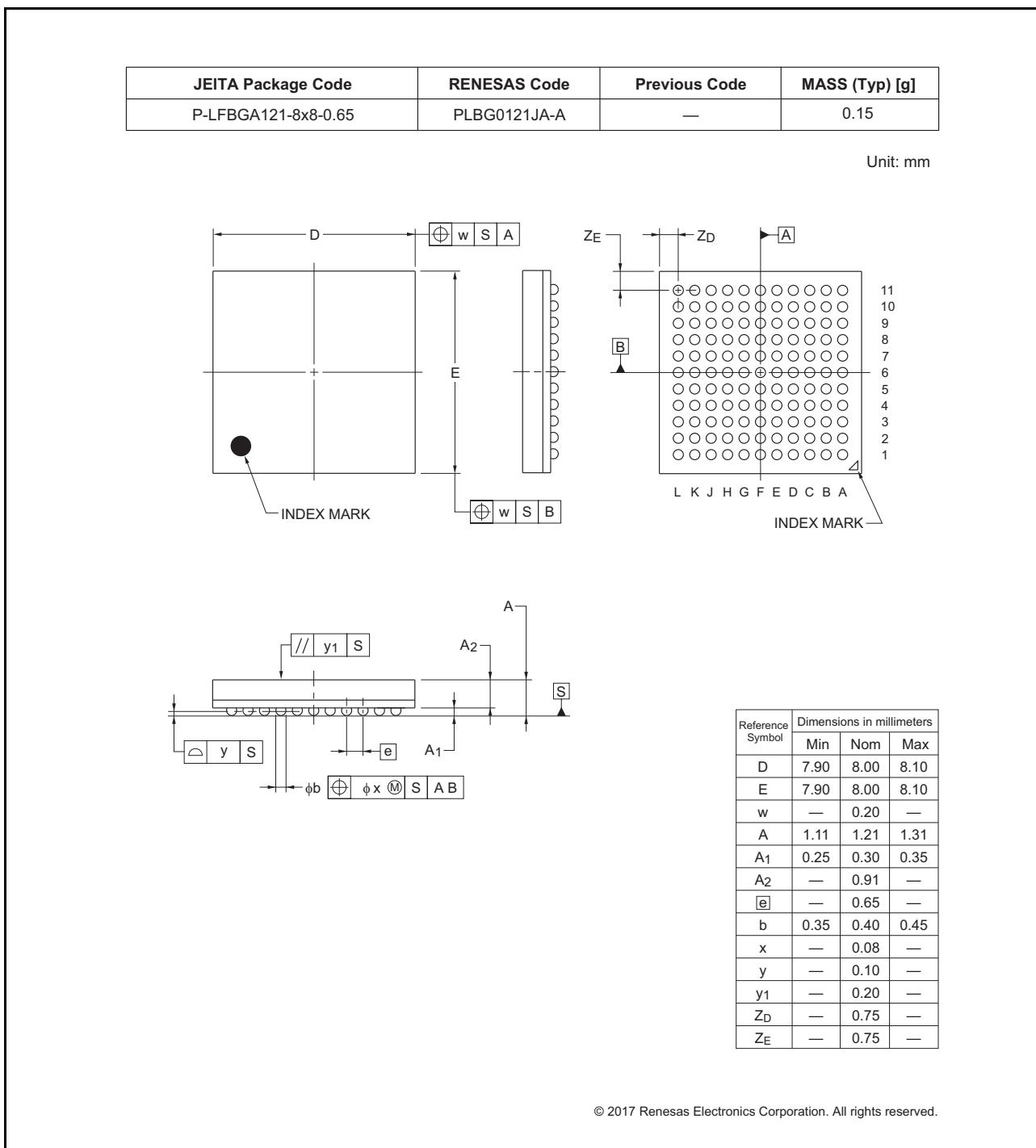
Table 2.73 ACMPLP characteristics

Conditions: VCC = 1.8 to 5.5 V

Parameter			Symbol	Min	Typ	Max	Unit	Test conditions	
Reference voltage range	Standard mode	IVREFn (n=0,1)	V _{REF}	0	-	VCC-1.4	V	-	
	Window mode*2	IVREF1	V _{REFH}	1.4	-	VCC	V	-	
		IVREF0	V _{REFL}	0	-	VCC-1.4	V	-	
Input voltage range			V _I	0	-	VCC	V	-	
Internal reference voltage			-	1.36	1.44	1.50	V	-	
Output delay	High-speed mode		T _d	-	-	1.2	μ s	VCC = 3.0 Slew rate of input signal > 50 mV/ μ s	
	Low-speed mode			-	-	5	μ s		
	Window mode			-	-	2	μ s		
Offset voltage*1	High-speed mode		-	-	-	50	mV	-	
	Low-speed mode		-	-	-	40	mV	-	
	Window mode		-	-	-	60	mV	-	
Operation stabilization wait time			T _{cmp}	100	-	-	μ s	-	

Note 1. When 8-bit DAC output is used as the reference voltage, the offset voltage increases up to 2.5 \times VCC/256.

Note 2. In window mode, be sure to satisfy the following condition: IVREF1 - IVREF0 \geq 0.2 V.

**Figure 1.3 BGA 121-pin**